Search Notes

Application/Contro	l No.	

Applicant(s)/Patent under Reexamination
LI ET AL.

10/064,251 Examiner

Art Unit

Habte Mered

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SEARCHED				
Class	Subclass	Date	Examiner	
370	221-223	2/23/2007	нм	
370	216-218	2/23/2007	НМ	
370	225,227	2/23/2007	НМ	
370	228	2/23/2007	НМ	
370	241,242	2/23/2007	НМ	
370	244	2/23/2007	НМ	
370	250,400	2/23/2007	нм	
370	401,406	2/23/2007	HM	
714	100,1,2	2/23/2007	нм	
709	239	2/23/2007	НМ	
379	221.1	2/23/2007	нм	
379	221.04	2/23/2007	нм	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Searched East DB:USPAT, UPGPUB, JPO, EPO	2/23/2007	НМ	
IEEE	2/23/2007	нм	
Palm Inventor's DB	2/23/2007	НМ	
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